

Overview of Algorithmic Methods in IC Reverse Engineering

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Technion



Outline

- IC Reverse Engineering in a nutshell
- Scan-based netlist extraction
- Partitioning
- The matching problem
- Structural Analysis
- Functional Analysis
- Summary and Future Directions

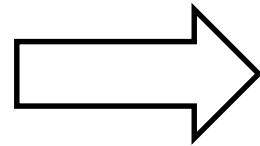
Ethics of Reverse Engineering



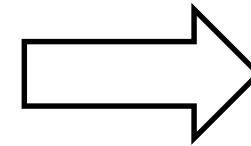
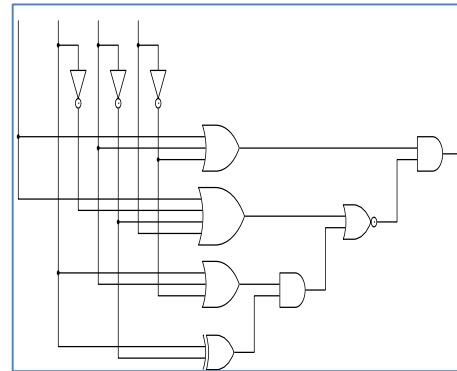
Ethics of Reverse Engineering

- Semiconductor Chip Protection Act (US) 1984 allows reverse engineering of commercial semiconductor products for **educational purposes**
- Ethical goals
 - Detect vulnerabilities that allow reverse engineering and propose countermeasures
 - Explore legitimate usages of the reverse engineering for defense
 - Hardware Trojans detection
 - IP theft detection

Reverse Engineering of an IC



Netlist



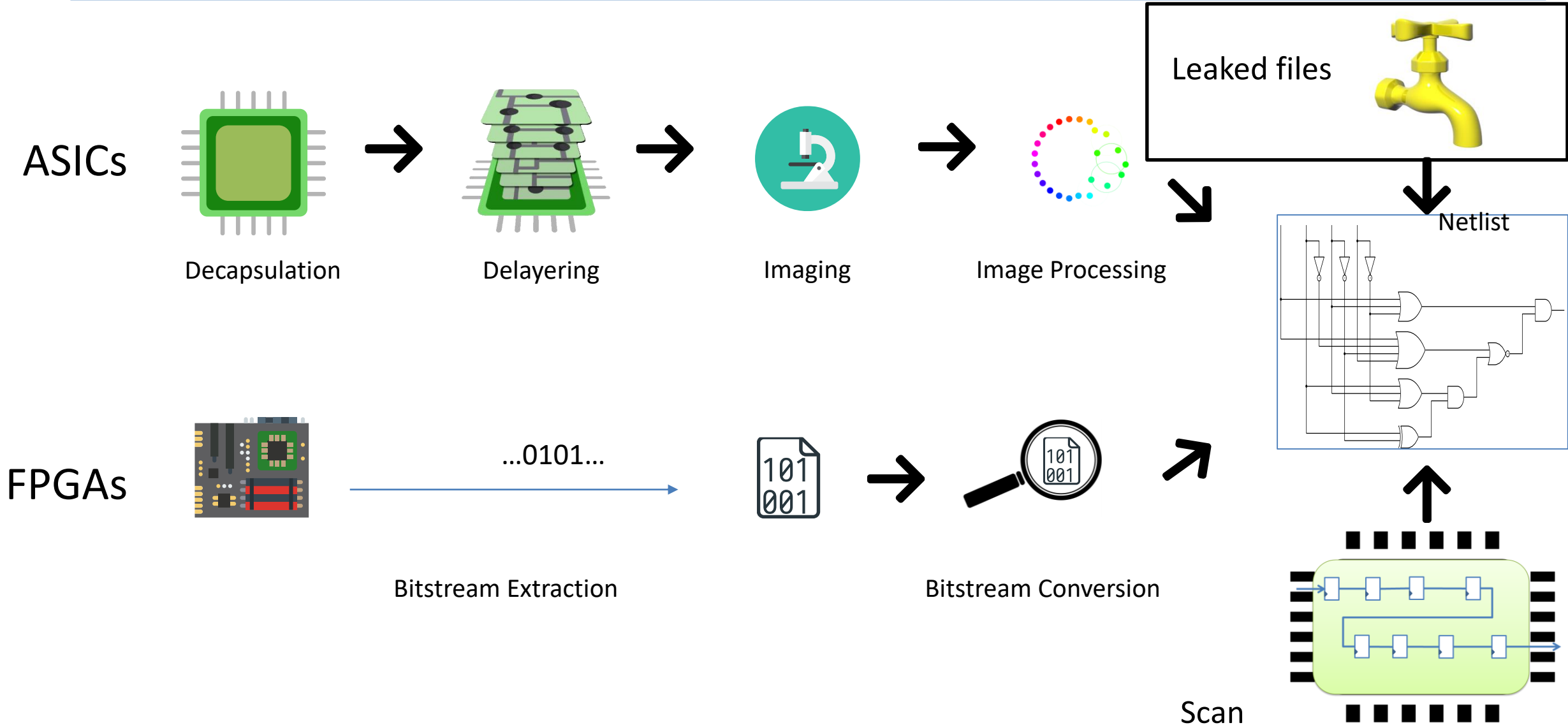
Phase 1 IC → Circuit

Phase 2 Circuit → Spec

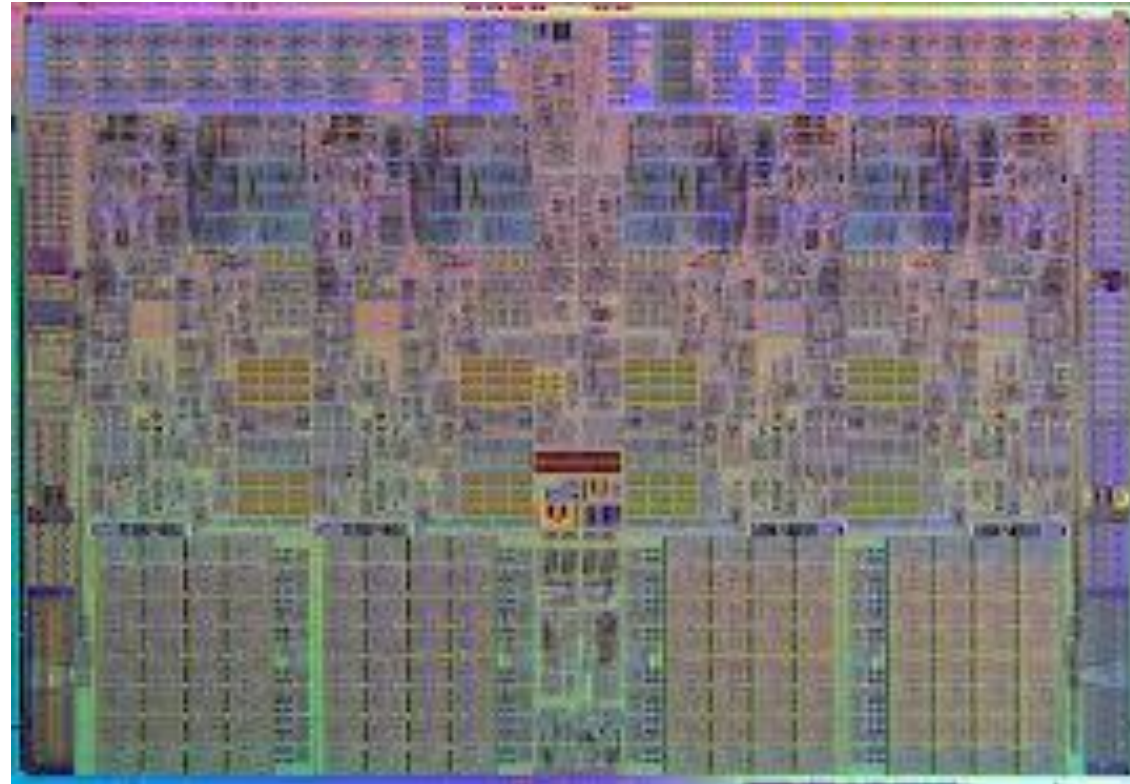
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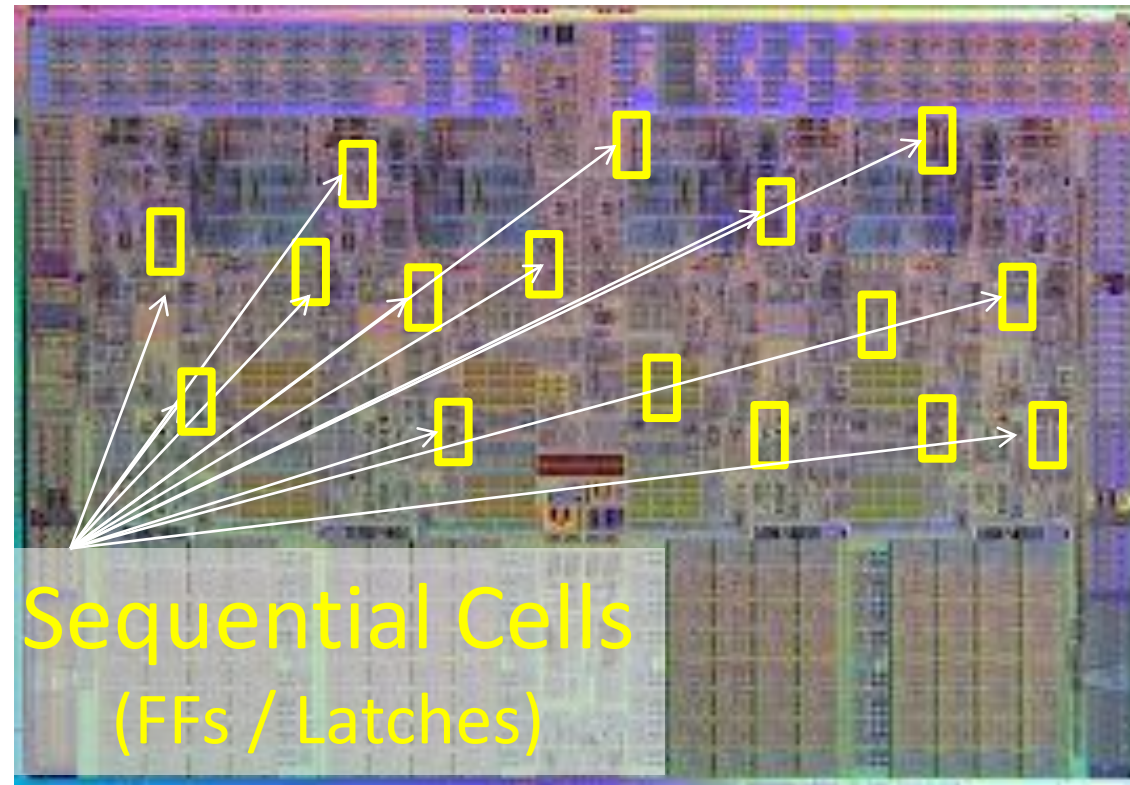
Netlist Extraction



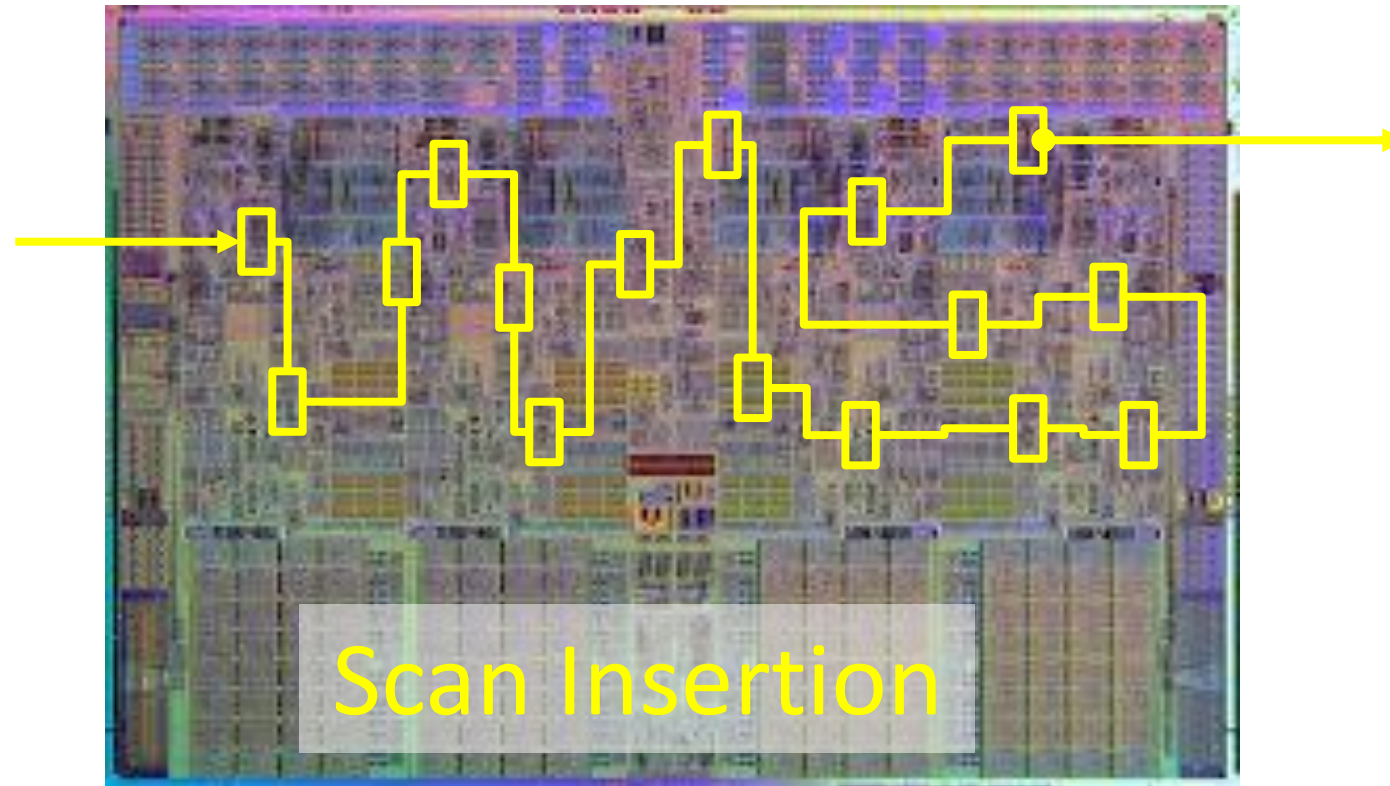
The Scan Technique



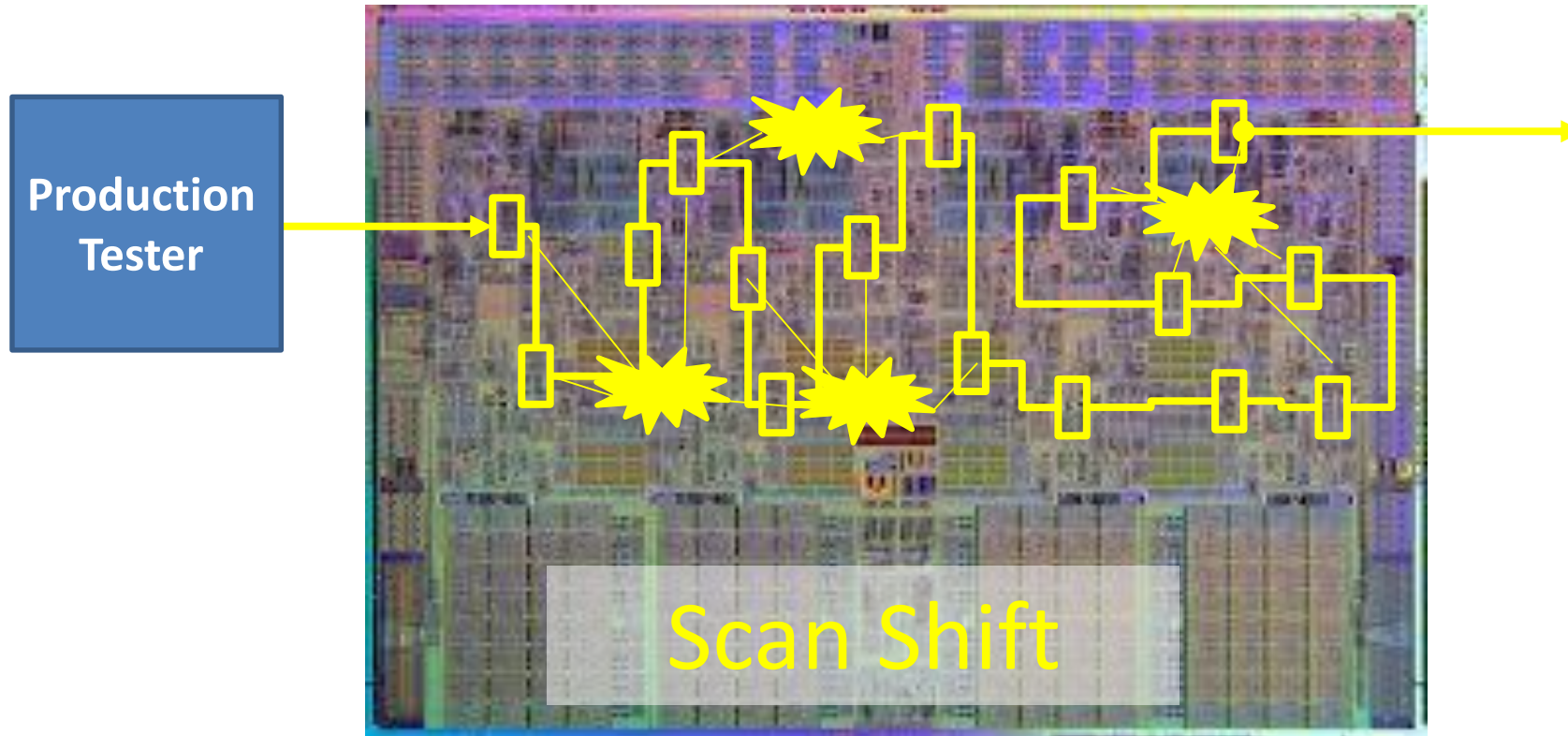
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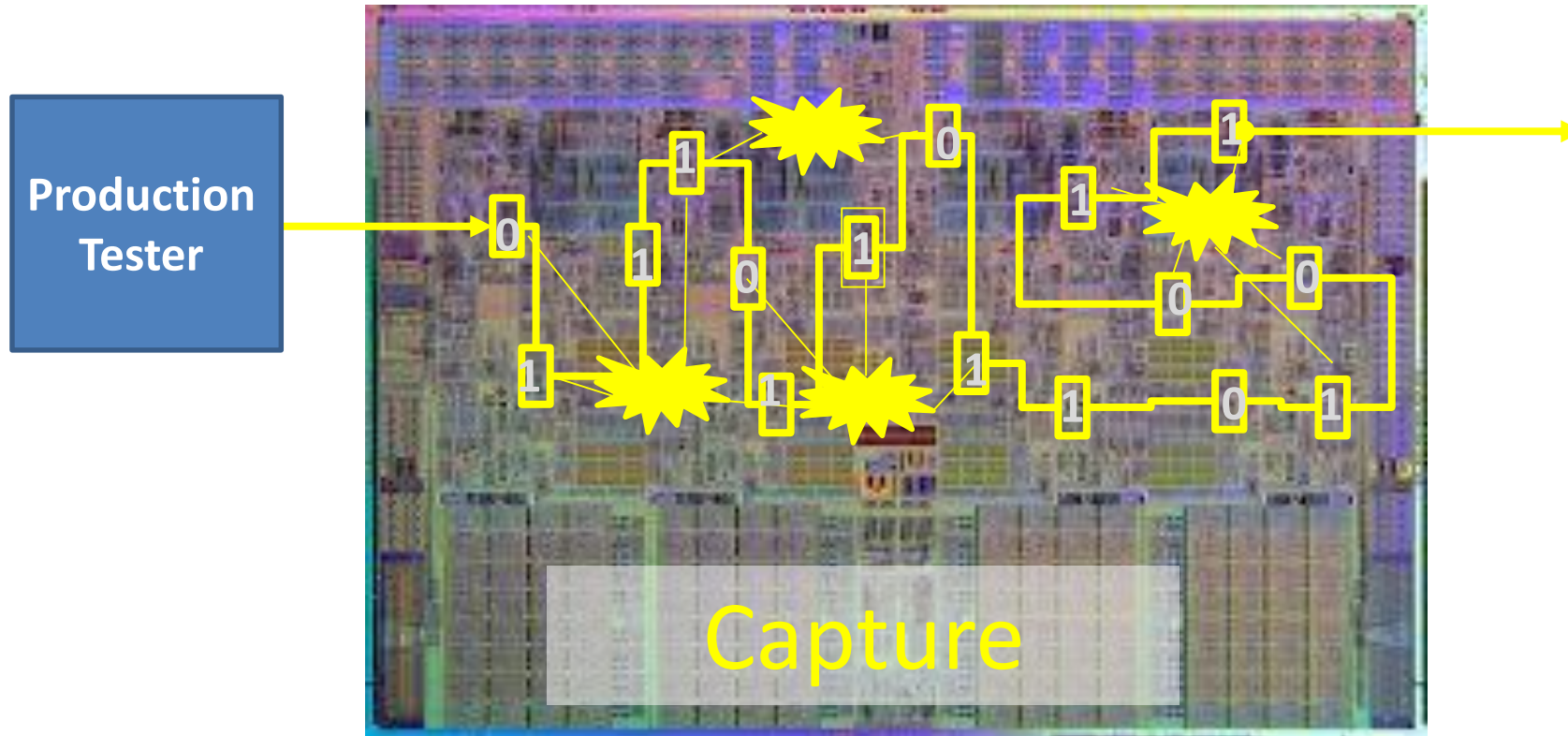
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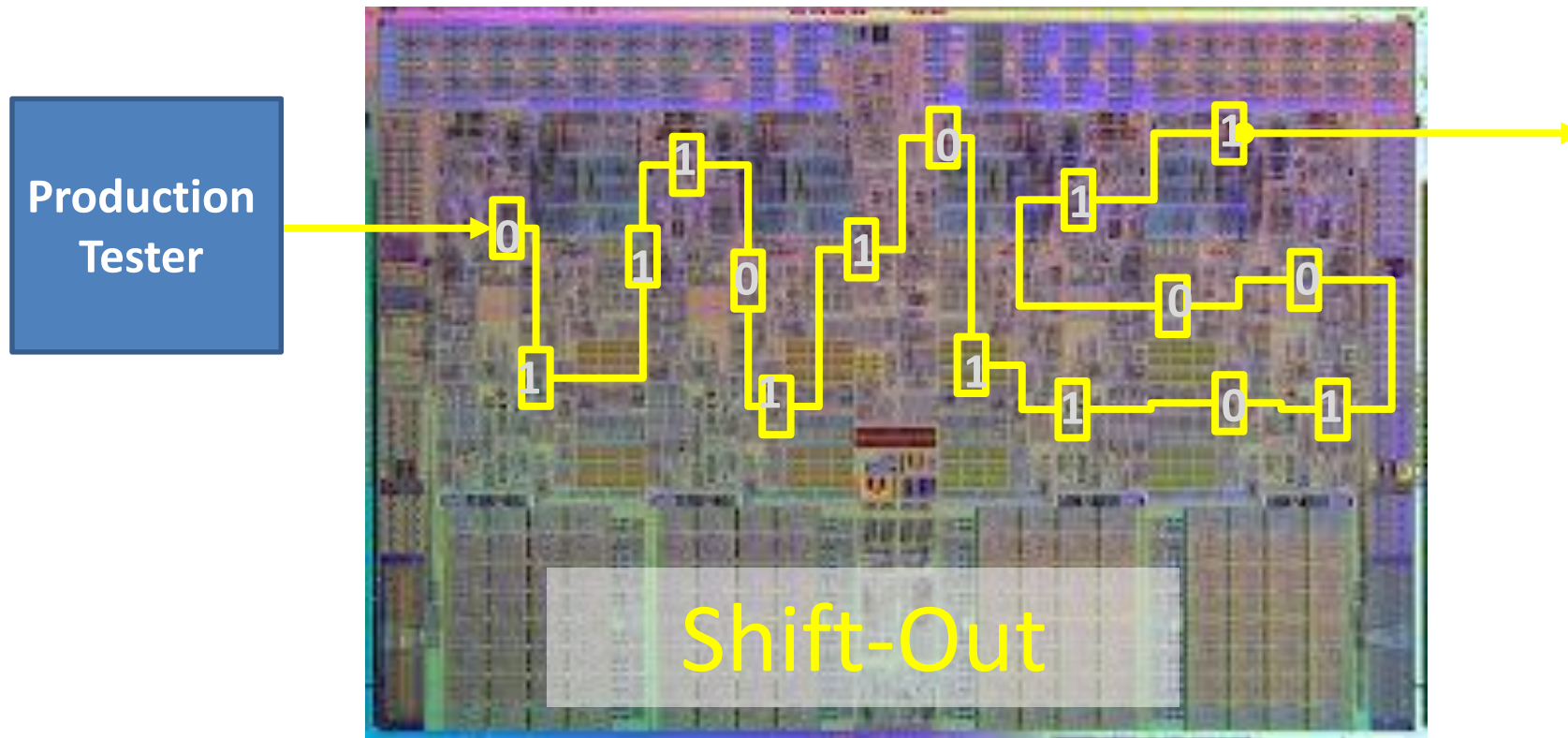
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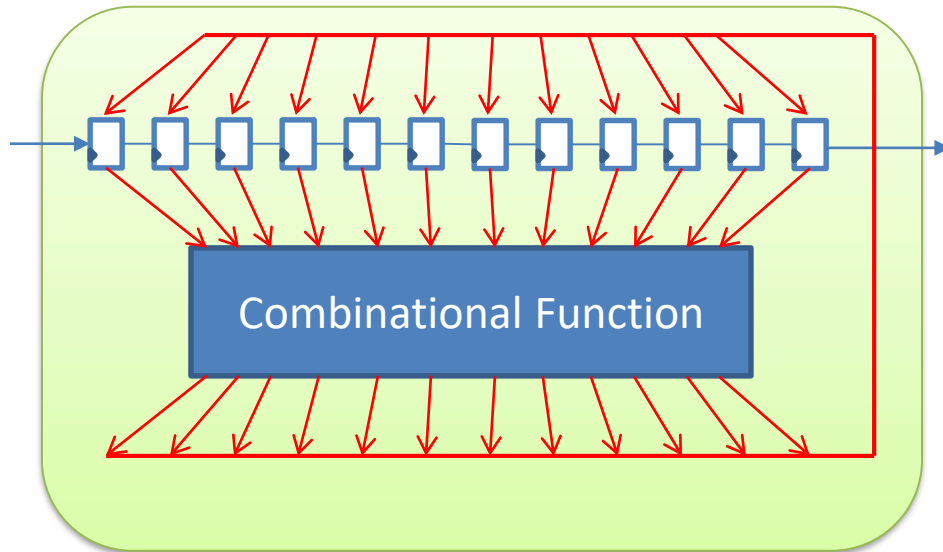
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The Scan Technique

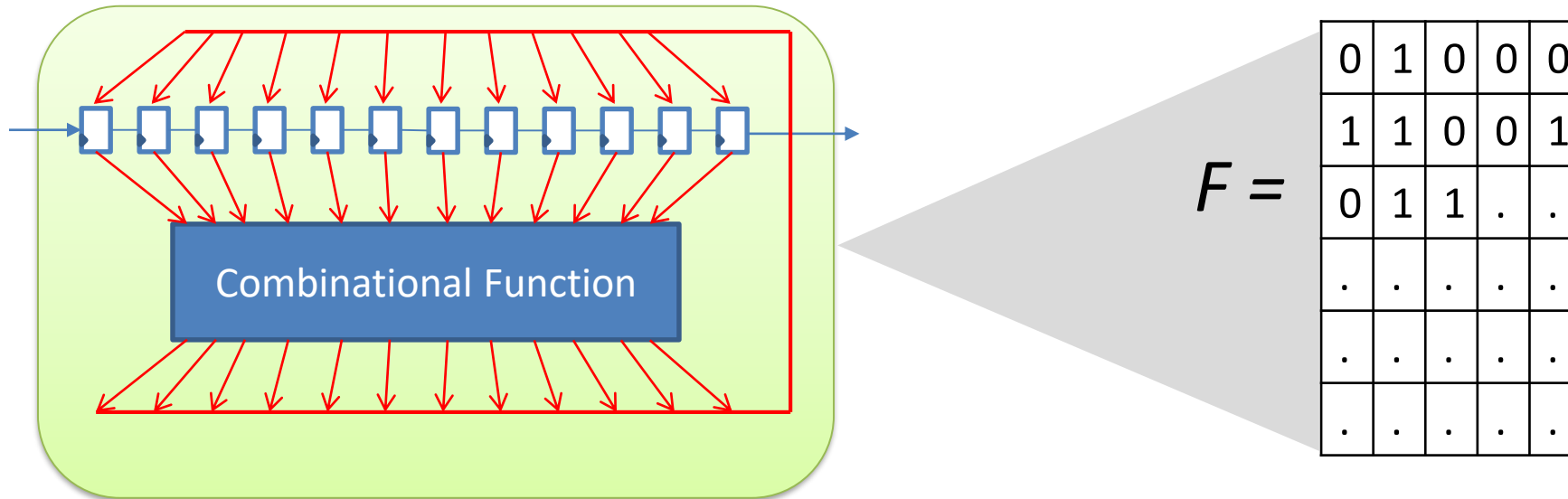


Unfolding Sequential Circuits with Scan



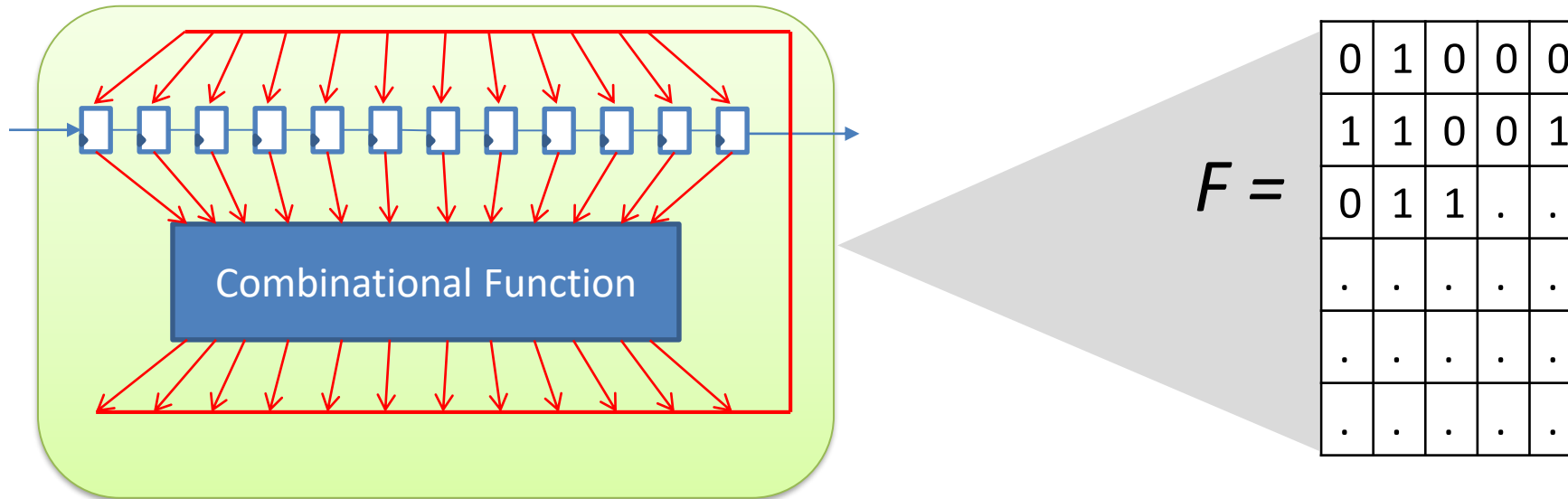
- Scan turns the IC to a stateless circuit
- Mapped to the **Boolean Function Learning** problem: $\{0,1\}^n \rightarrow \{0,1\}^n$

Unfolding Sequential Circuits with Scan



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- Exhaustive Search: Extract the Truth Table by running queries for all inputs

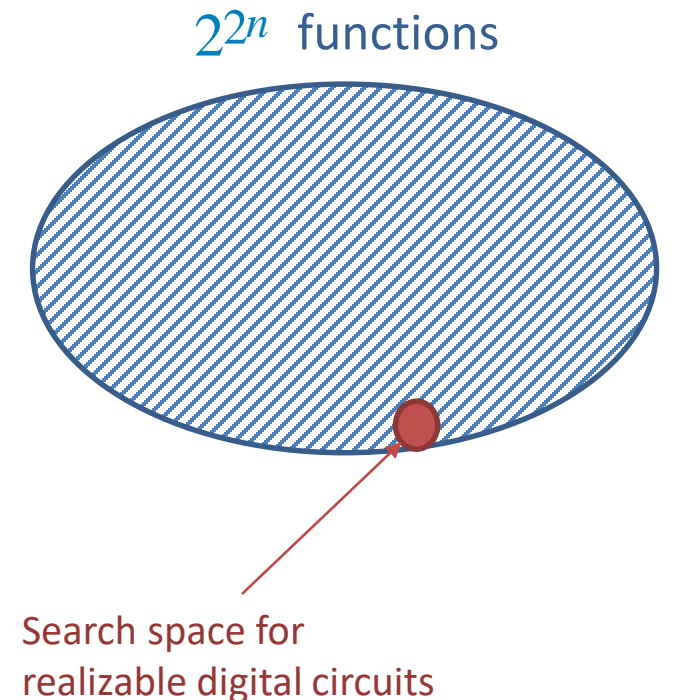
Unfolding Sequential Circuits with Scan



- Scan turns the IC to a stateless circuit
- Mapped to the **Boolean Function Learning** problem: $\{0,1\}^n \rightarrow \{0,1\}^n$
- Exhaustive Search: Extract the Truth Table by running queries for all inputs
- **Exponential Size: 2^n**

Shannon Effect

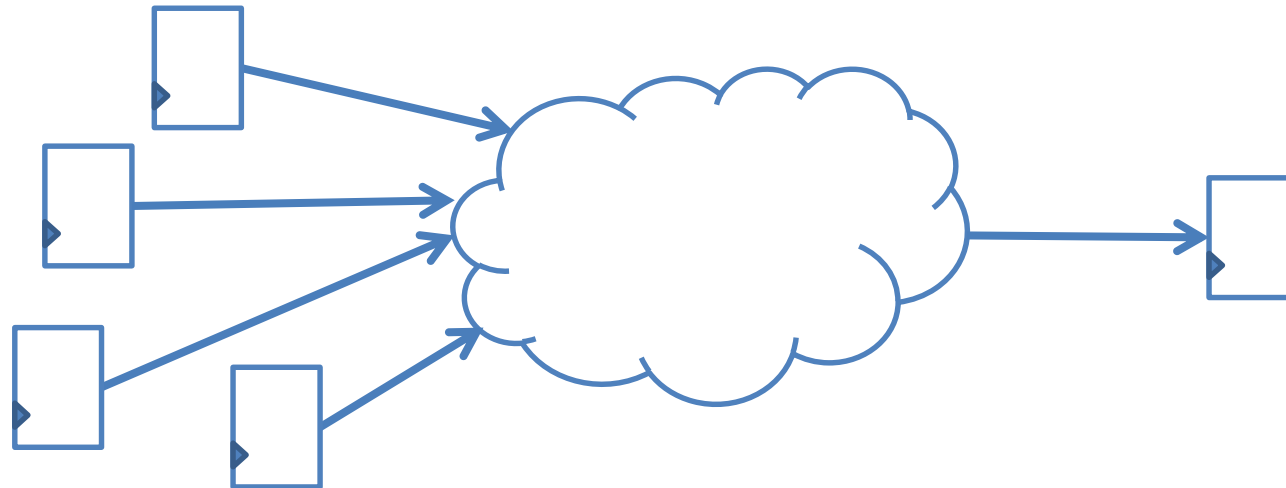
- Shannon Effect: “almost all” Boolean functions have a complexity close to the maximal possible ($\sim O(2^n)$) for the uniform probability distribution
- Corollary: For large n , “almost all” Boolean functions are not realizable in VLSI technology



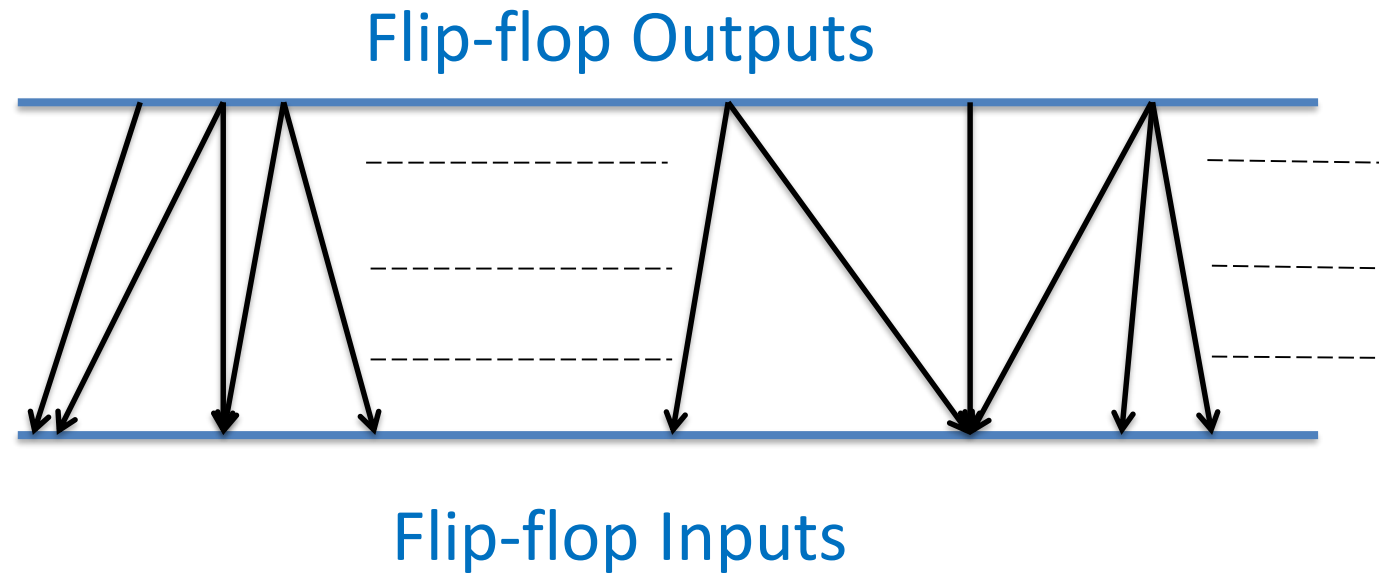
Limited Transitive Fan-in

- In practice, logic cones have limited number of inputs:

Transitive Fan In = K



Dependency Graph



- Bipartite graph represents flip-flop dependencies
- The goal: Find dependencies
- Complexity: $2^n \rightarrow 2^k$: Scalable with the chip size

The K-Junta Algorithm

$$y = f(\vec{x}), \vec{x} = \{x_1, x_2, \dots, x_i, x_{i+1}, \dots, x_j, \dots, x_n\}$$

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$$\vec{a} = \{0, 0, \dots, 0, 0, 0, 0, \dots, 0, 0\}, f(\vec{a}) = 0$$

Generate random queries $y = f(\vec{x})$

$$\vec{b} = \{1, 0, \dots, 1, 0, 1, 0, 0, \dots, 0, 1\}, f(\vec{b}) = 1$$

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Relevant Variable

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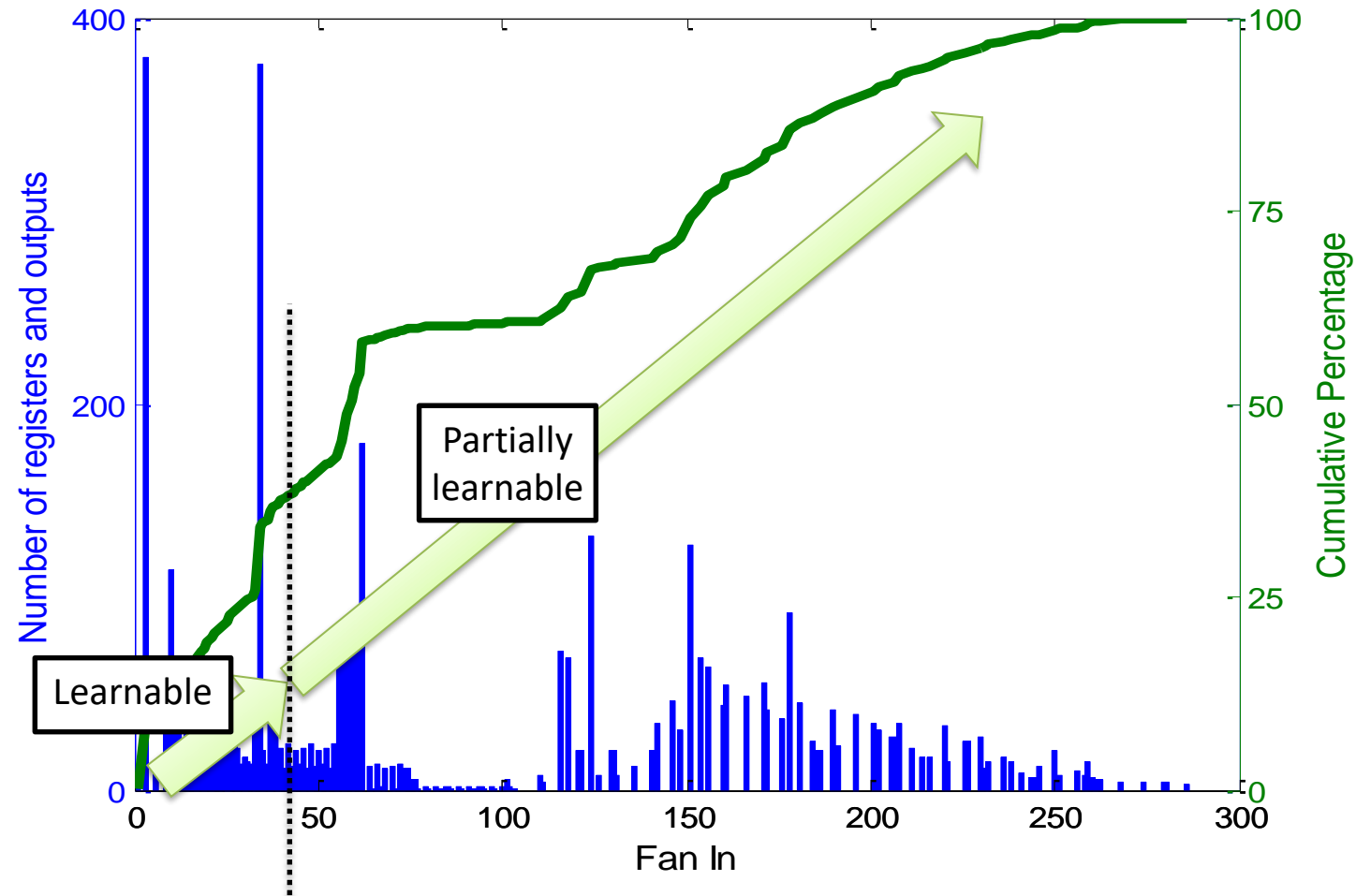
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$$O(n \cdot \log n \cdot k \cdot 2^k)$$

Relevant Variable


Transitive Fan-in for ITC'99 benchmark



Assumptions

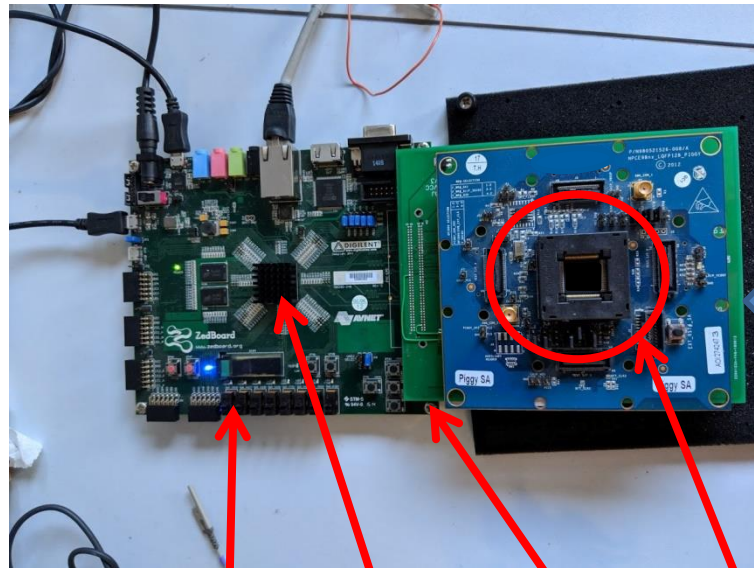
- Physical access to the device
- Scan operation protocol is known
 - Vendors use proprietary protocols
 - There are standard solutions by EDA vendors
- Scan control is not protected or protection is defeated

Assumptions

- Physical access to the device
- Scan operation protocol is known
 - Vendors use proprietary protocols
 - There are standard solutions by EDA vendors
- Scan control is not protected or protection is defeated
- Or self-owned device 

Scan-based netlist extraction setup

Server



Vector out

Vector in

Network

FPGA board

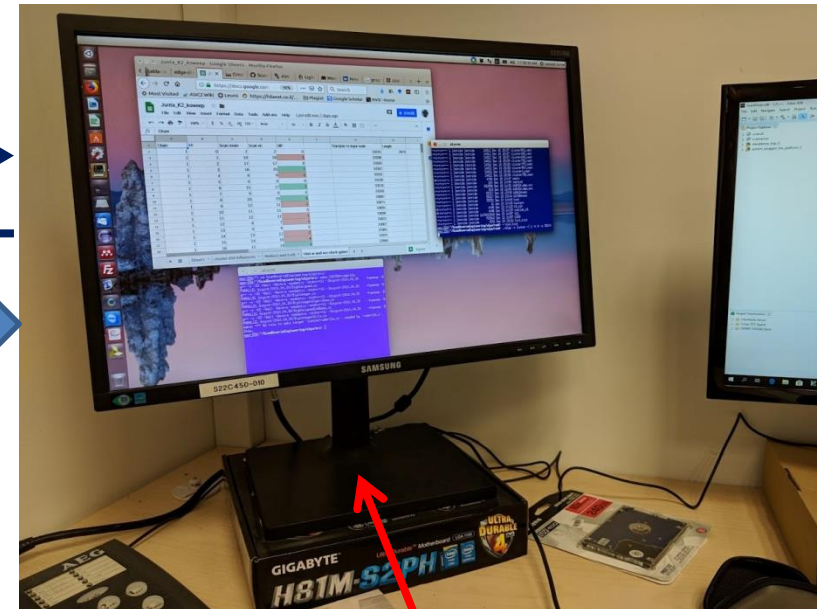
Connection board

FPGA + ARM

Scan tester and server SW

Target

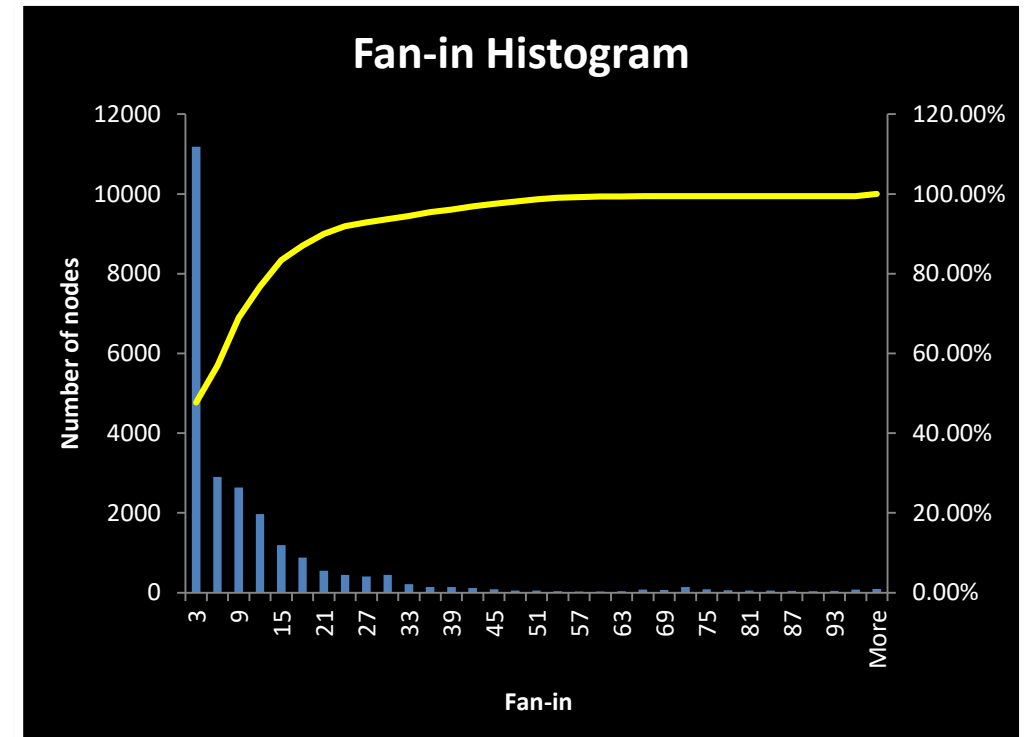
Client



Algorithm software

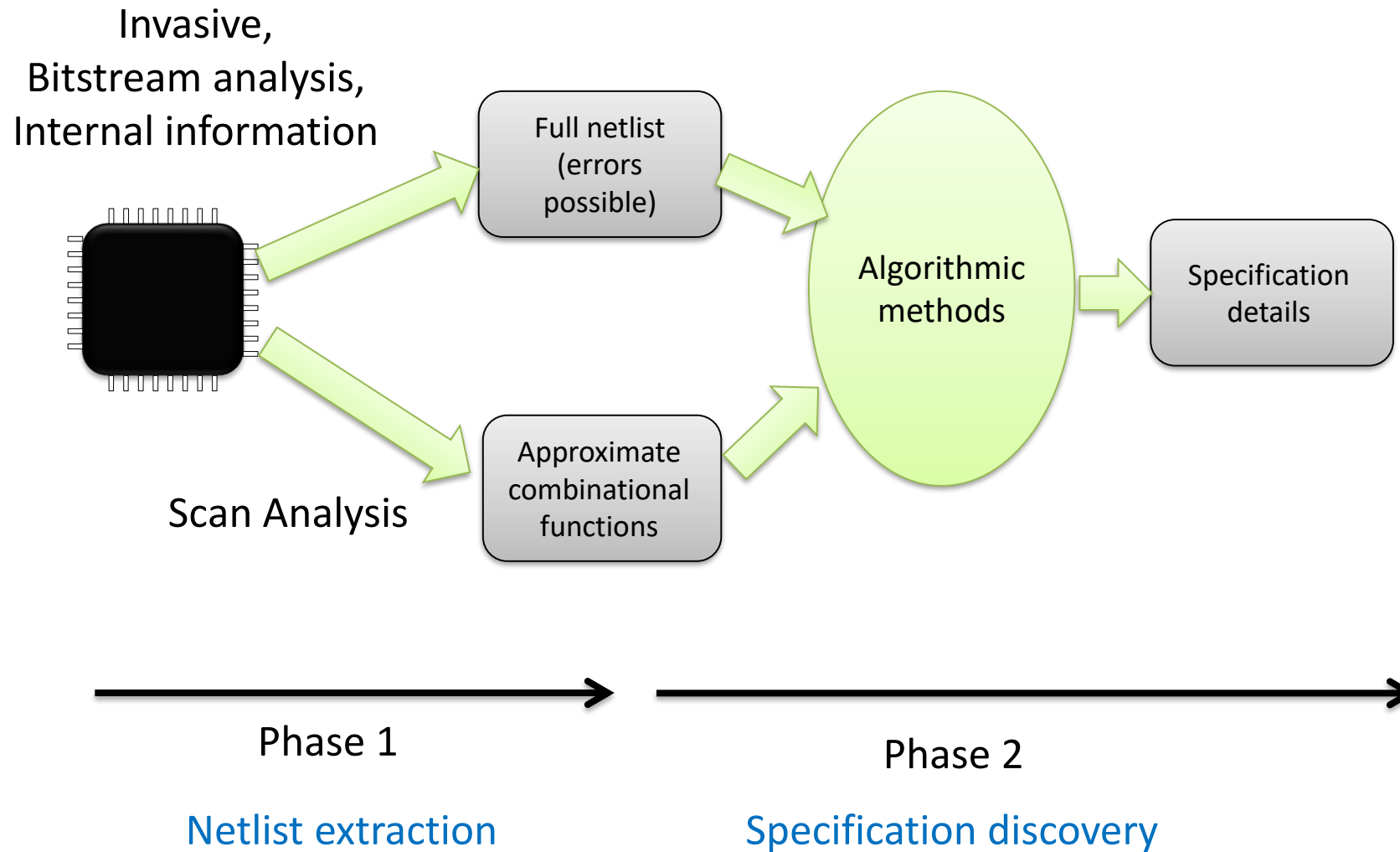
Fan-in analysis

- Partial data: not all dependencies discovered
 - Estimation: vast majority is there
 - Longer runs reveal few more links



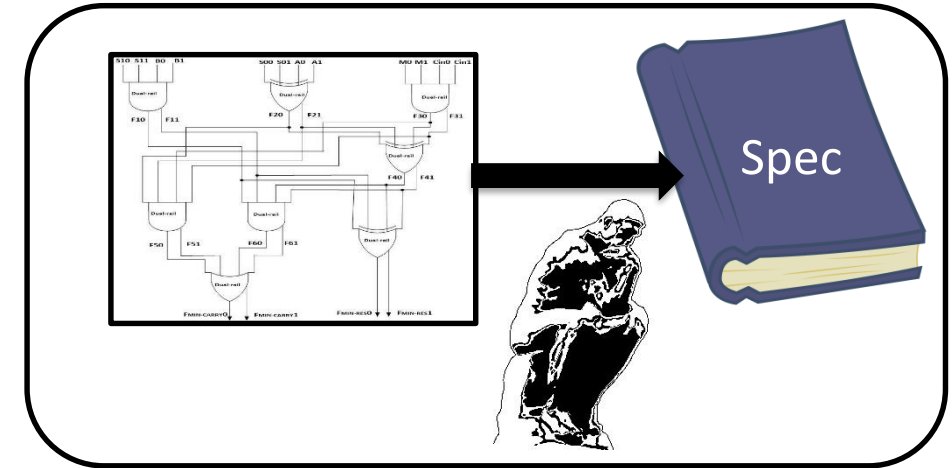
- ~95% of logic cones can be directly reverse engineered at the logic function level

The two phases



Specification Discovery

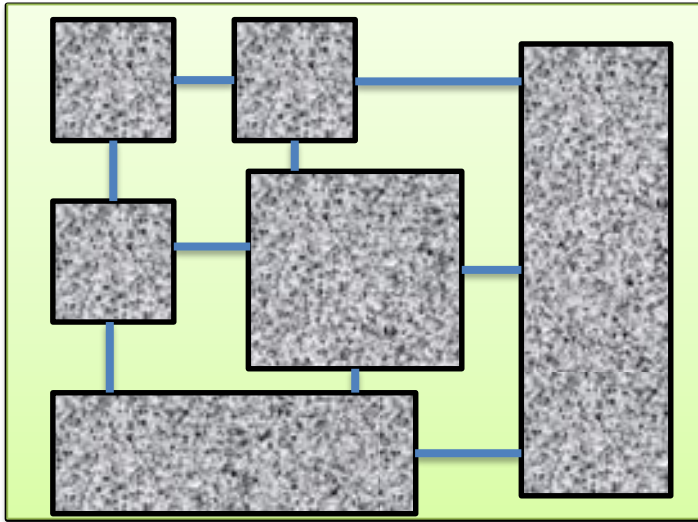
- What actually the spec is?
- No universal definition or format
- Can be
 - Finding familiar elements
 - Translating to a higher level language
 - Goal dependent, e.g. finding specific properties



Outline

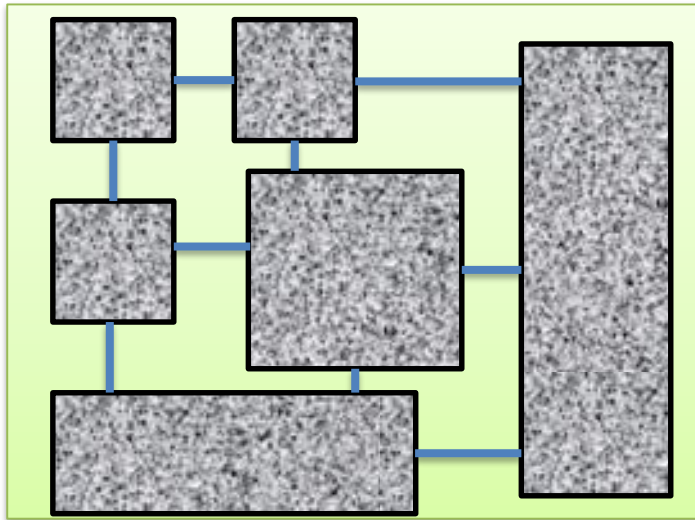
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Circuit Partitioning



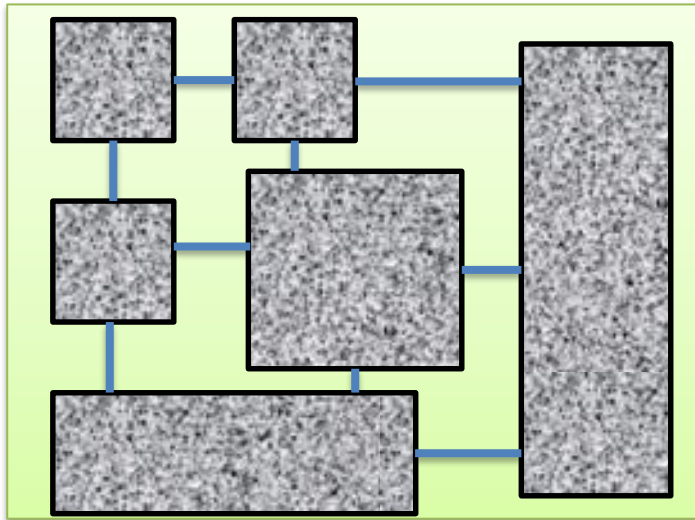
- Find basic structure in the flat graph

Circuit Partitioning



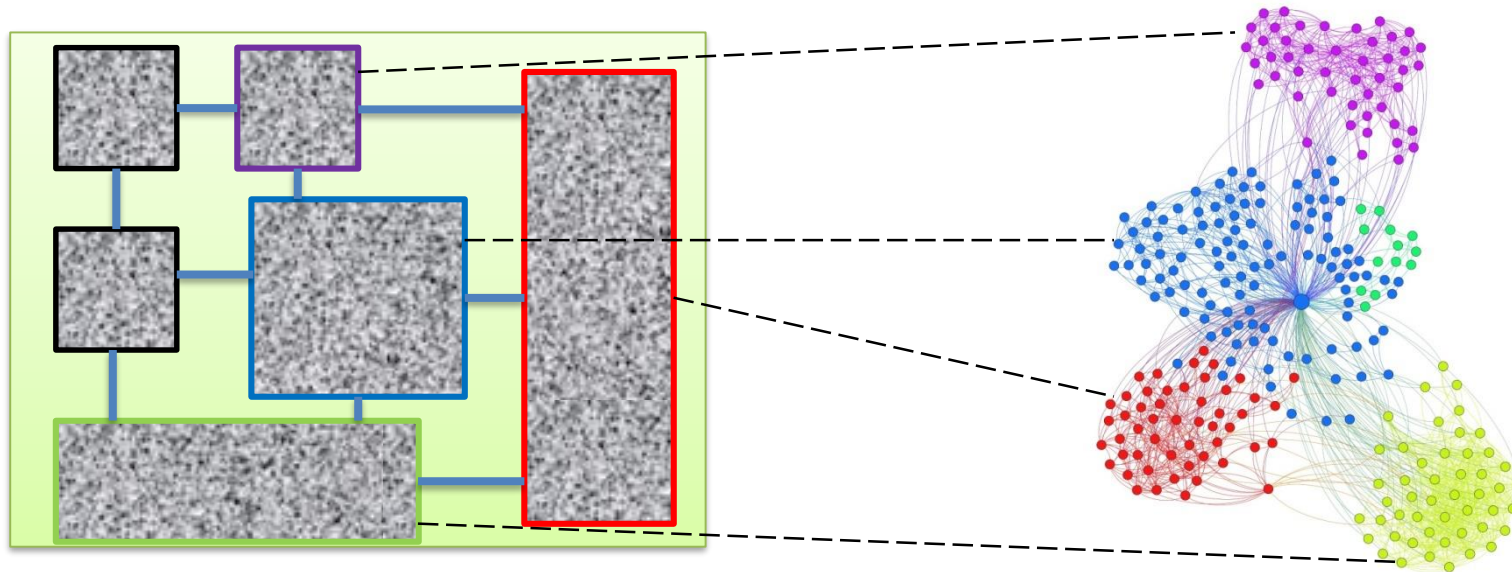
- Goal: match the source design partitioning

Circuit Partitioning



- Goal: match the source design partitioning
- Criteria: wire density

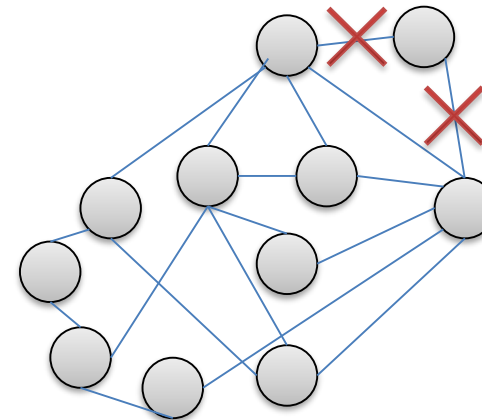
Circuit Partitioning



- Goal: match the source design partitioning
- Criteria: wire density
- Method: graph clustering

Minimum cut

- Partition a graph by removing minimum number of edges
- Widely used in the VLSI CAD tools
- **Top-down** approach
- Poor choice for our problem:
 - **Fixed** number of partitions
 - **Uneven** split



More top-down methods

- Min-Ncut
 - Normalized min-cut

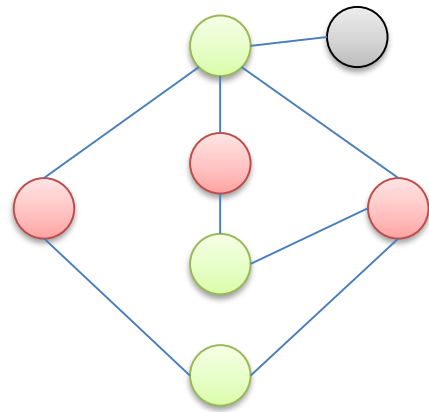
$$NCut(A, B) = \frac{cut(A, B)}{assoc(A, V)} + \frac{cut(A, B)}{assoc(B, V)}.$$

- Modularity maximization
 - Find best partition to maximize modularity

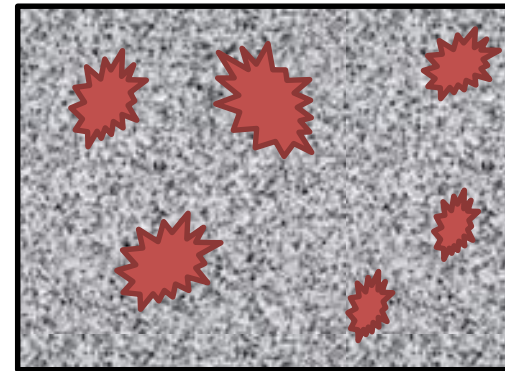
$$Modularity(G_i \in G) = \frac{|E|_{G_i} - |E|_{G^*_i = \{V_{G_i}, E_{random}\}}}{|E|_G}$$

Shared Nearest Neighbors (SNN)

- Every pair of nodes with >threshold shared neighbors are assigned to the same cluster



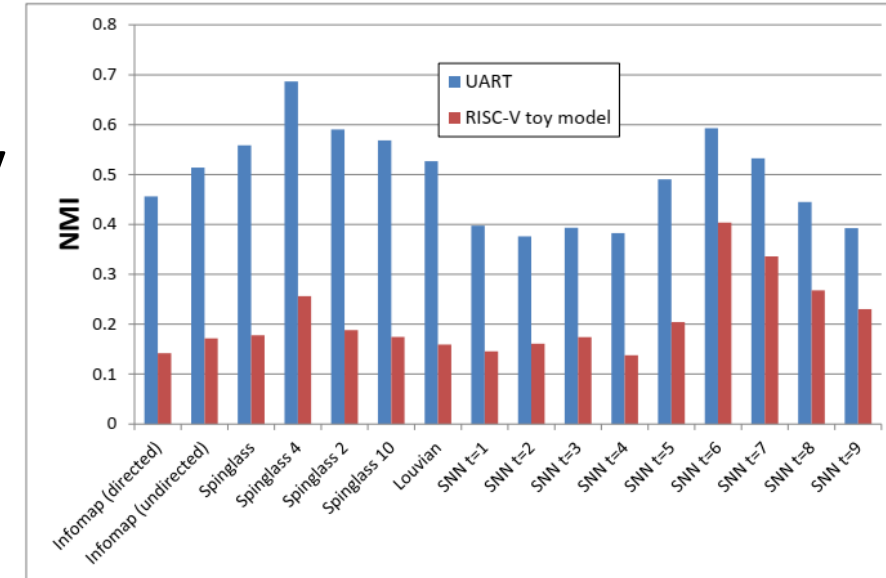
SNN (threshold=2)



Bottom-up

Clustering algorithms evaluation

- **Goal:** match the original design hierarchy
- **Metric:** Should reflect the goal
- **NMI:** Normalized Mutual Information
 - Information theoretical metric



$$NMI = \frac{I(\Omega, \hat{\Omega})}{[H(\Omega) + H(\hat{\Omega})]/2}$$

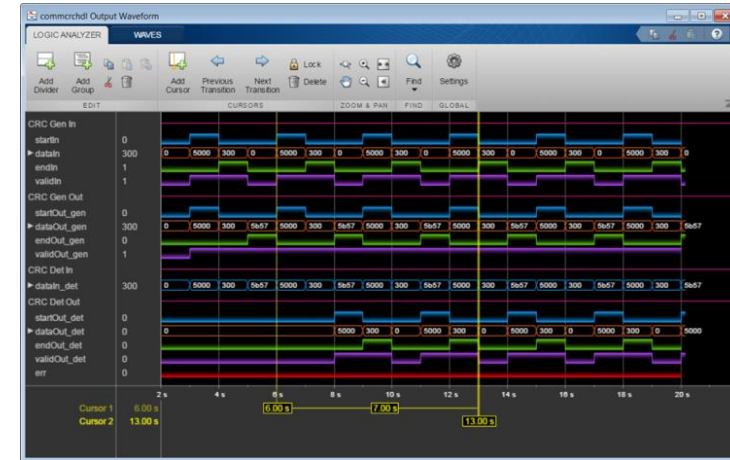
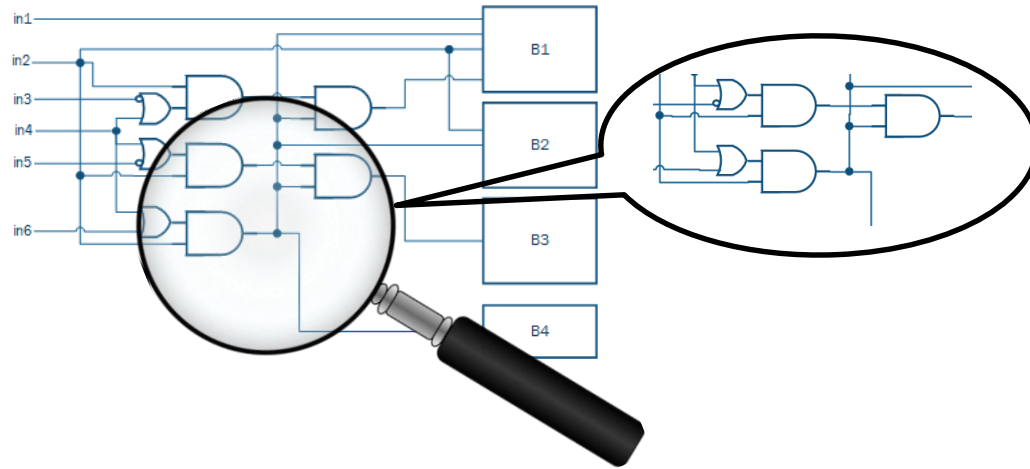
Mutual Information

Entropy

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Matching against a library

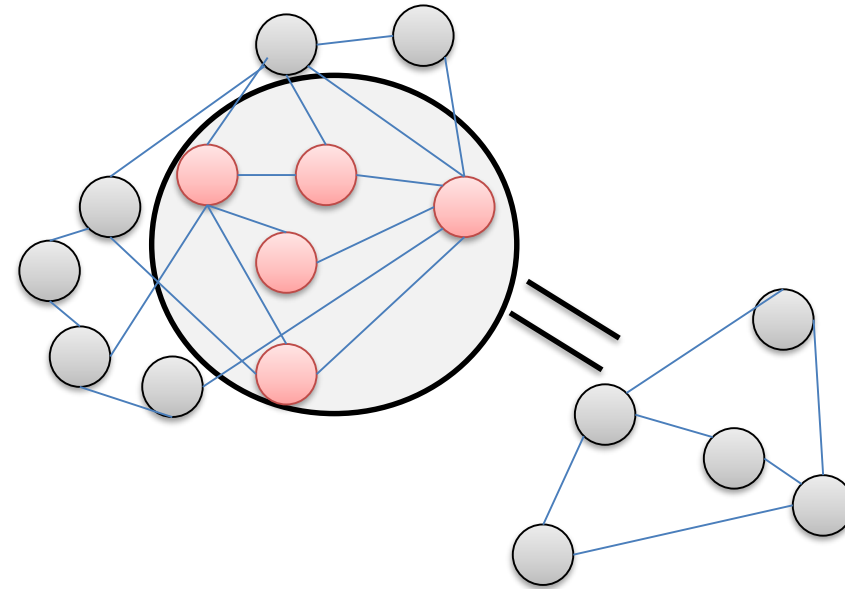


- Structural Analysis
 - Syntactic match
 - Isomorphism
 - Less flexible

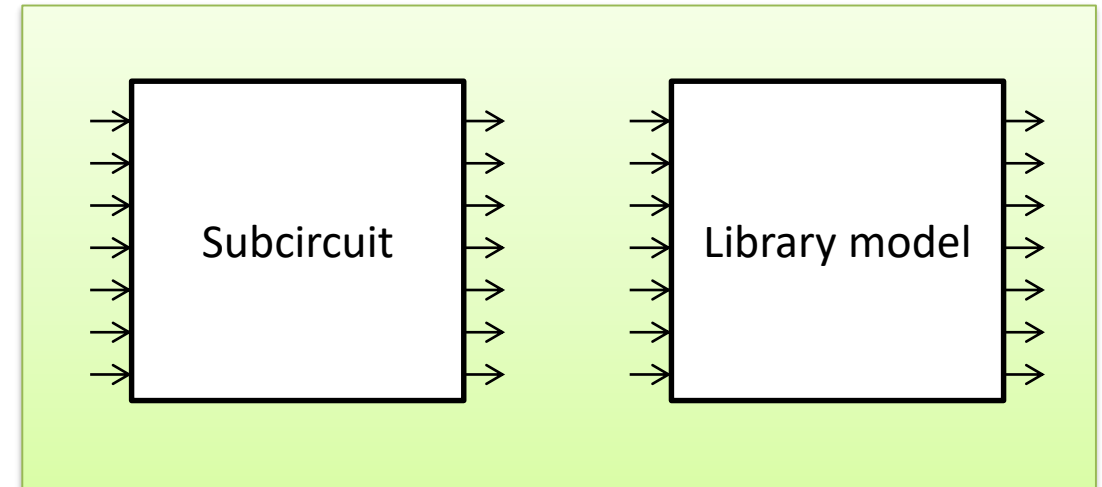
- Functional Analysis
 - Semantic match
 - Functional identity
 - Static / simulations

Matching library components

- Subgraph isomorphism
 - Structural match
 - NP-complete
- Heuristics
 - Dimension reduction
 - Signatures

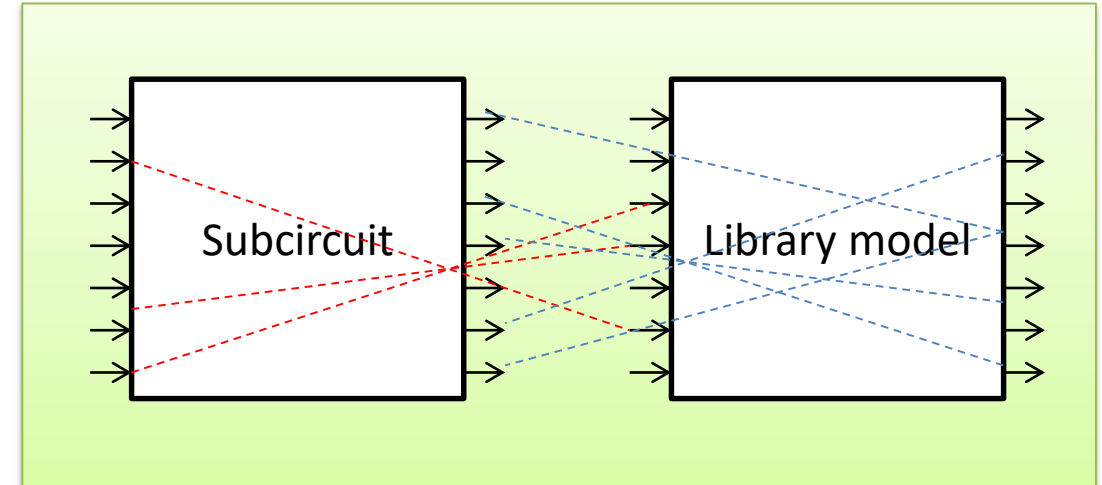


NPNP-invariant matching



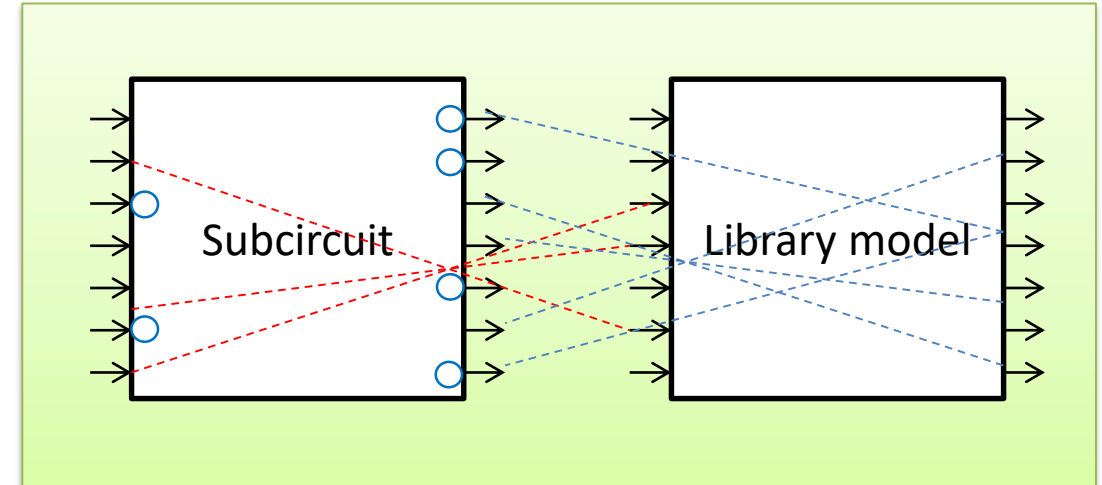
NPNP-invariant matching

- Input/output permutation

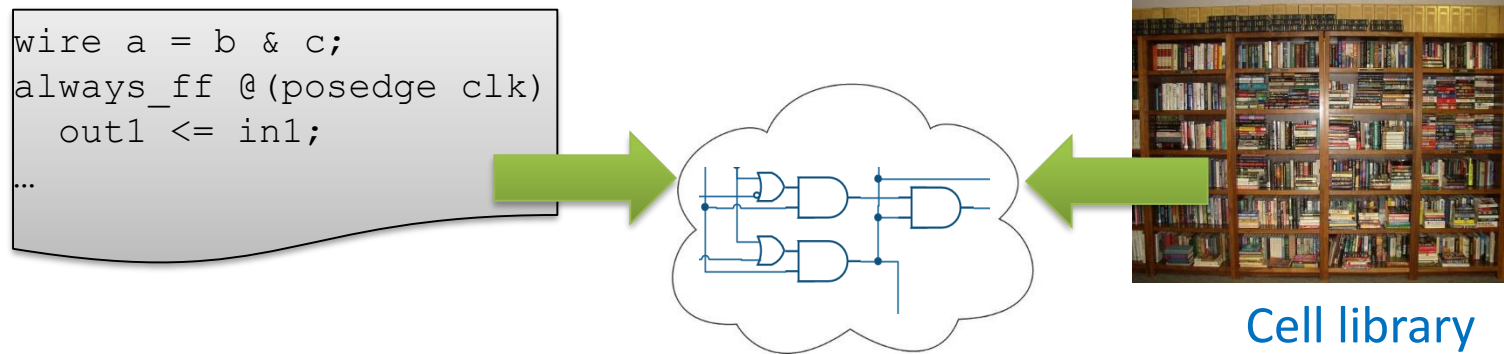


NPNP-invariant matching

- Input/output permutation
- Input/output negation



Technology mapping

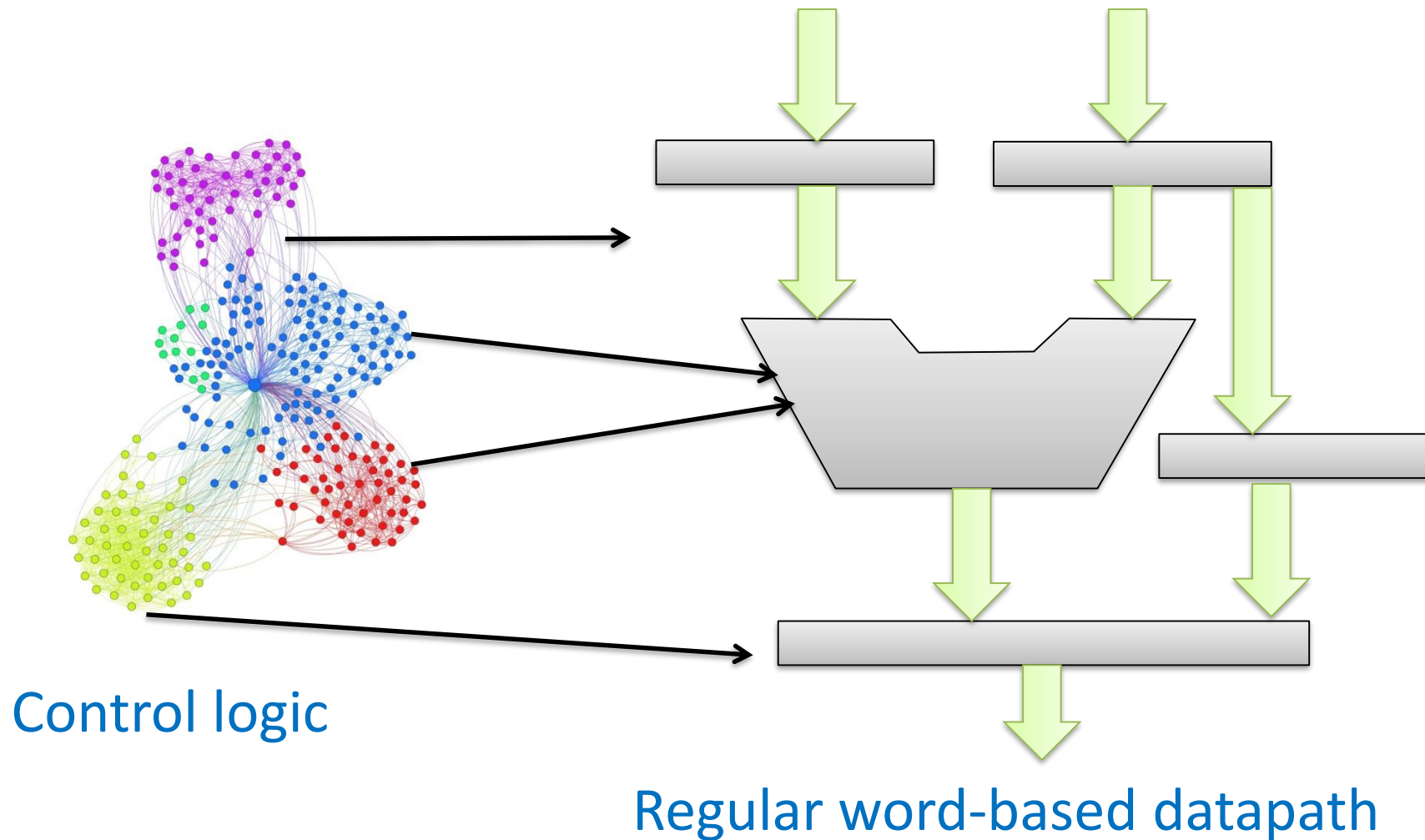


- RTL synthesis
 - Map generic logic to technology cells
 - npnp-invariant matching

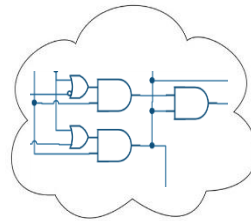
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Looking for more structure



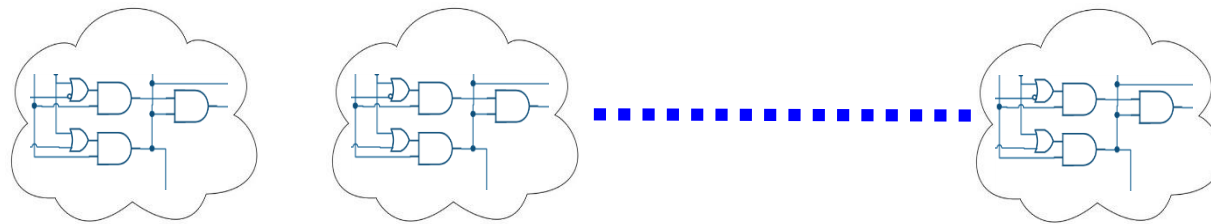
WordRev: construct bit slices



6-Feasible cut

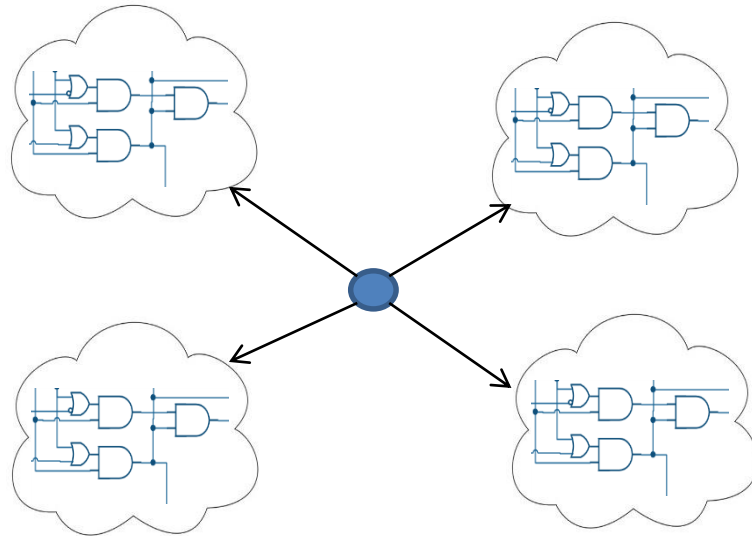
(K-Feasible cut of $N = K$ nodes that completely define the value of N)

WordRev: group equivalent slices

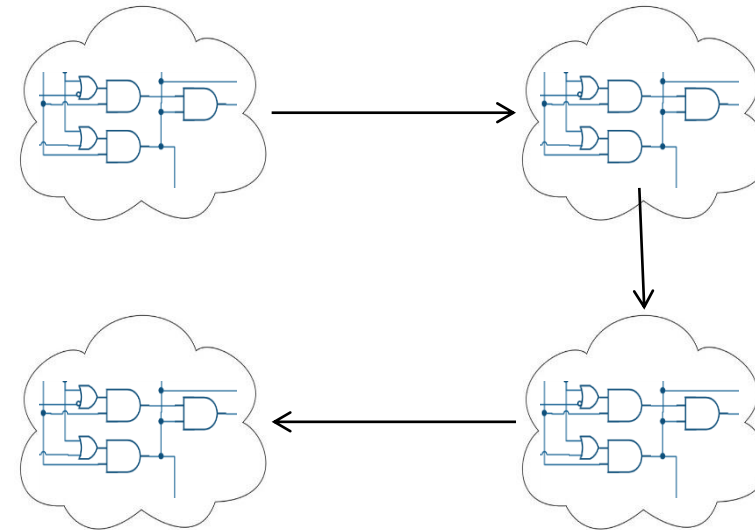


Permutation-invariant Boolean matching

WordRev: group by connections

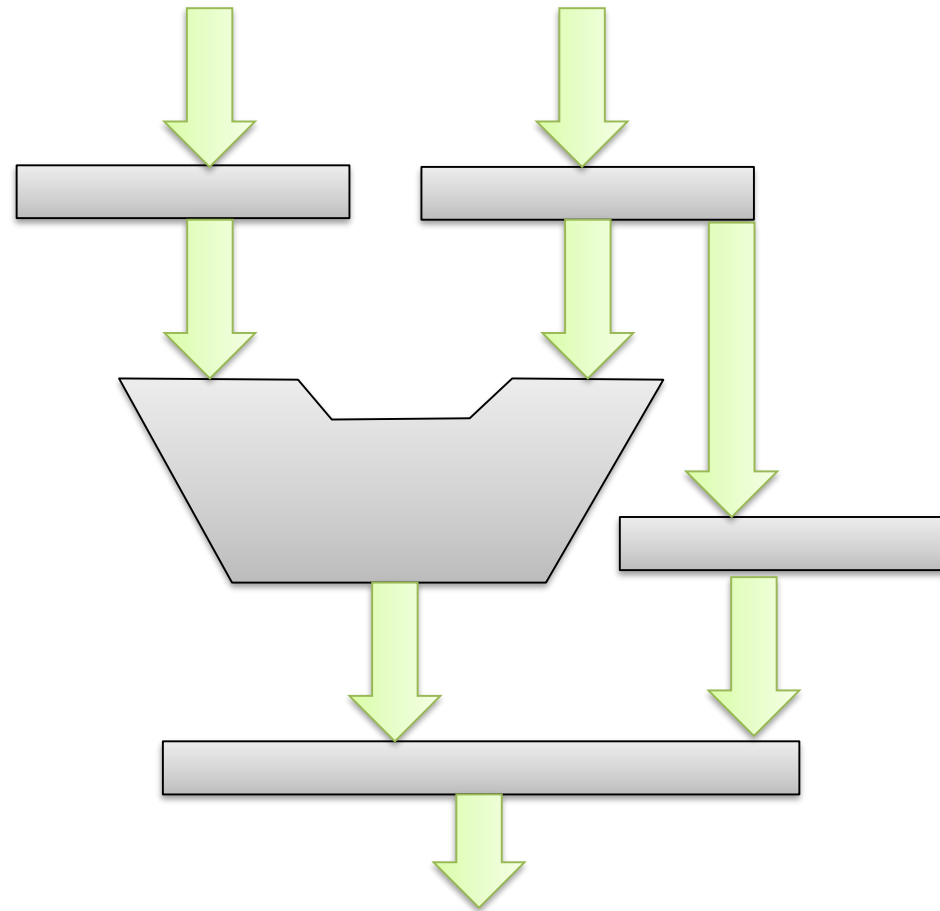


Parallel connection
(e.g. MUX select)

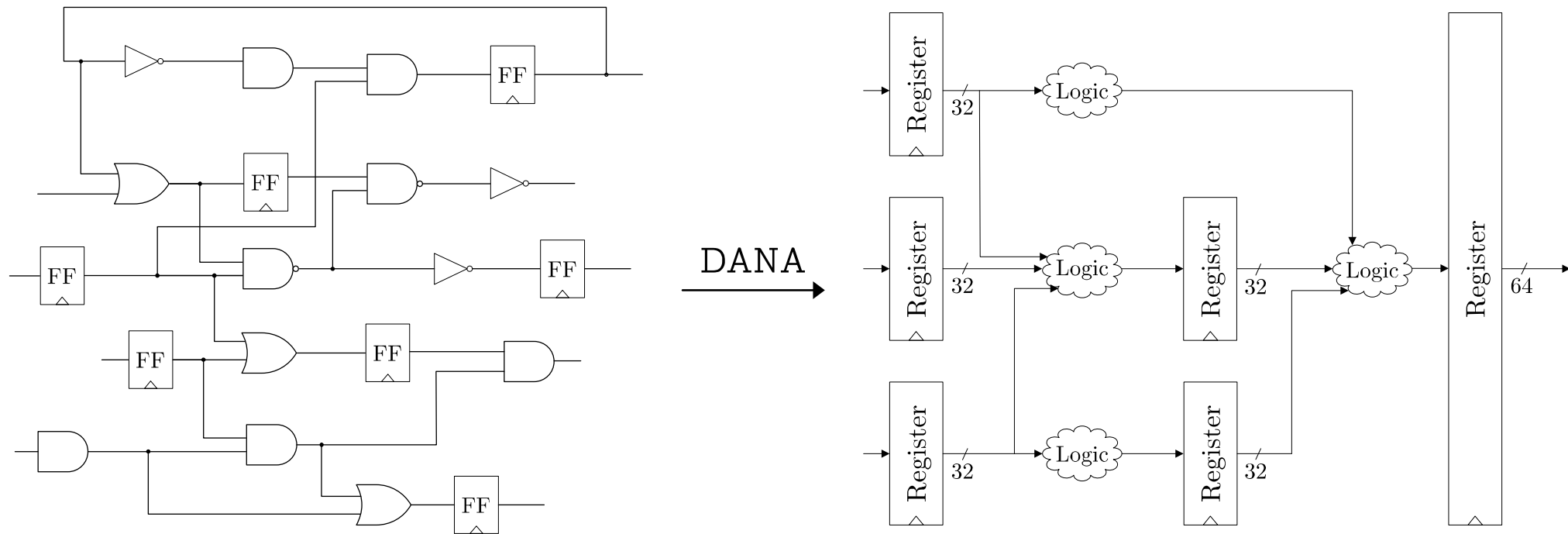


Serial connection
(e.g. carry propagation)

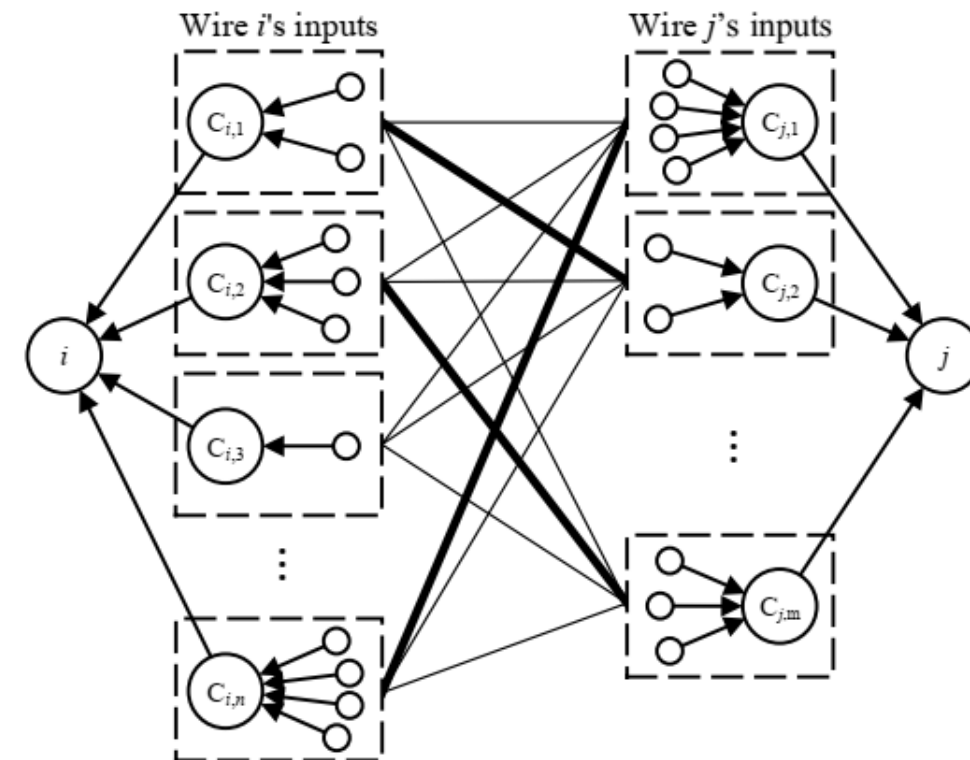
WordRev: propagate word structures



DANA - Universal Dataflow Analysis for Gate-Level Netlist Reverse Engineering



- Detecting registers in data words
 - Loose topological comparison of fan-in structures
- Preprocess to simple gates
- Recursive search
 - Similarity metrics
 - Based on number of inputs
 - Connecting nodes with *similarity > threshold*



Extracting state machines

- Mark registers with feedback path as FSM registers
 - Too many false positives

Extracting state machines

- Mark registers with feedback path as FSM registers
 - Too many false positives
- Narrowing down
 - Select registers that control datapath
 - Group registers that have the same enable signal
 - Group registers that have shared gates in their combinational feedback path

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Logic Equivalence Check

- Massively used in the VLSI design process
- Uses anchors
 - Named registers
 - Hierarchical boundaries
- Usually combinational match only
 - Still a SAT problem, but there is a structure

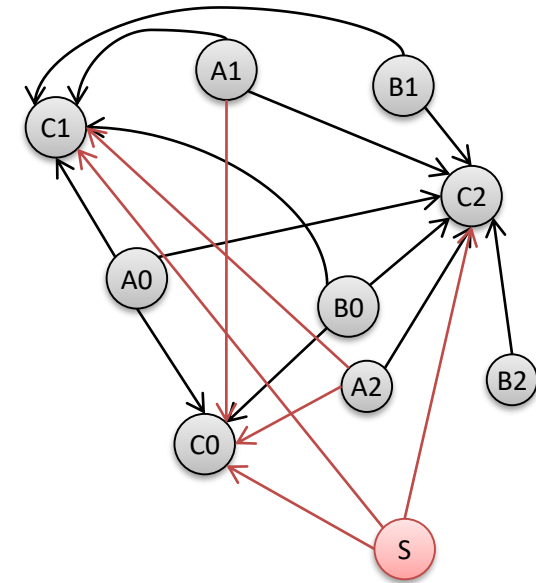
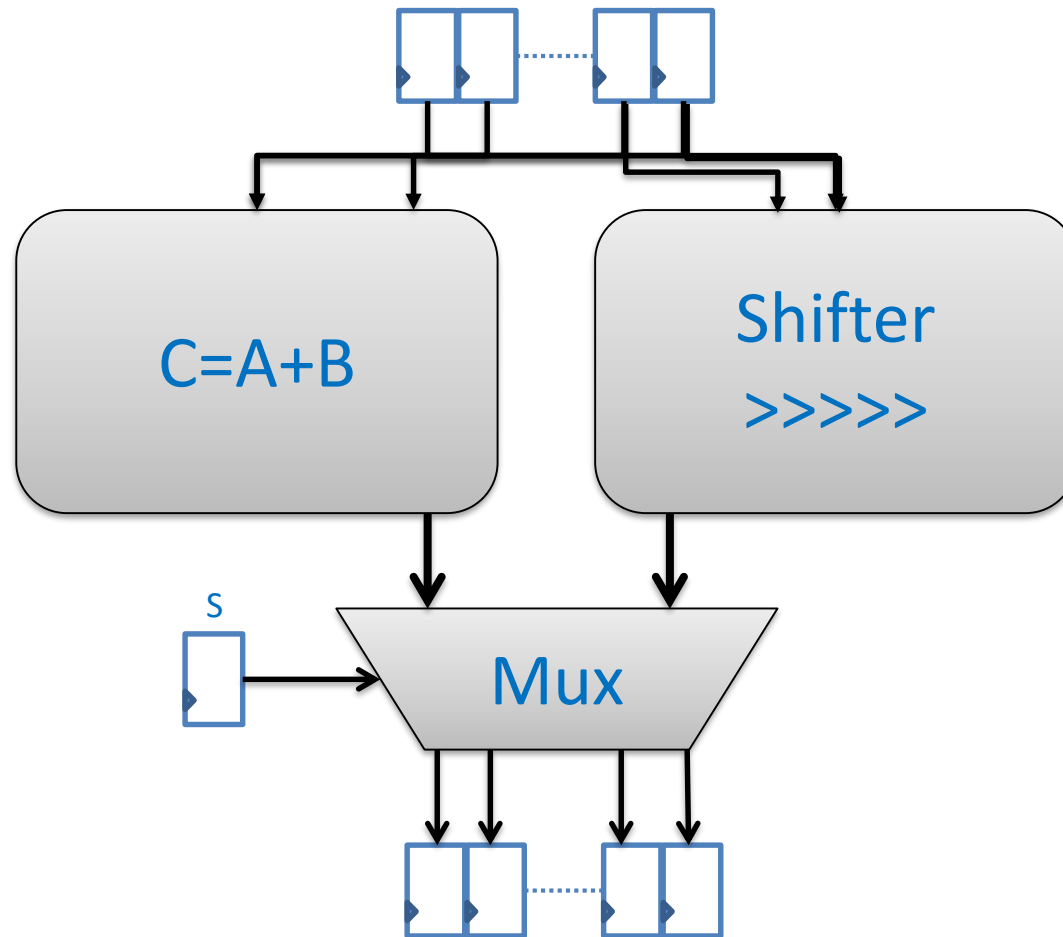
Machine learning for RE

- Some unsupervised learning used for clustering
- Can the full ML power be harnessed for RE?
- Problem: insufficient dataset

Using CNN for circuit recognition

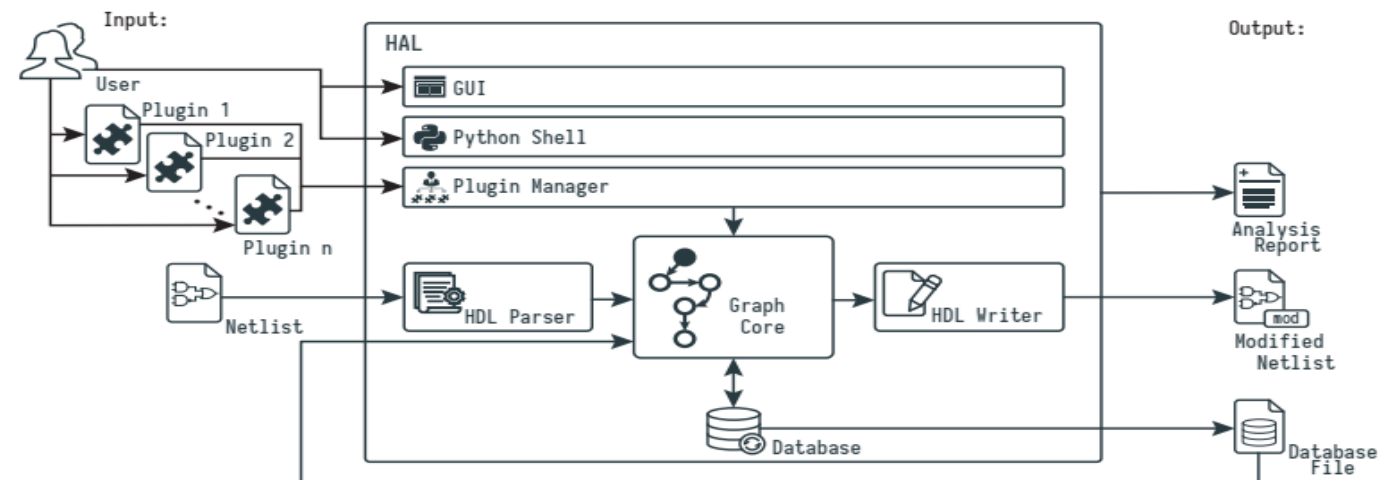
- Map a circuit to a library of 4-LUTs
- 222 isomorphism classes to make the LUT npn-invariant
- Existence vectors: classes of adjacent elements
- Reduced existence matrix is fed to CNN
- Total set of 250 synthetic circuits
- Efficient for a small number of classes
 - One class (detect whether multiplier is present): **97% accuracy**
 - 9 classes: **75% accuracy**

Spectral Graph Methods



Reverse Engineering Tools

- Commercial
 - ChipWorks
 - Texplained ChipJuice (phase 1)
- Academia
 - Degate (phase 1)
 - HAL

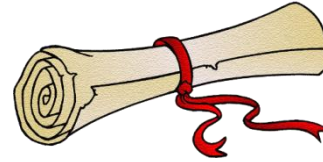


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- Algorithmic Reverse Engineering Tools
- **Summary and Future Directions**

Future research directions

- Uniform output format
 - Streamline the research
 - Evaluation baseline and common metrics
- Quantifying success
 - How to measure spec information
 - Is number of classified gates the right metric
- Graph methods
 - Take advantage of the big advancement in the social network analysis



Future research directions

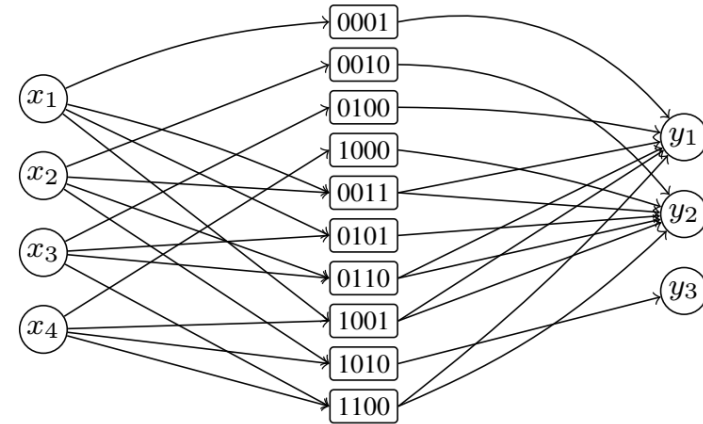
- Functional analysis
 - Use Boolean function properties
- Machine learning
 - Generate a synthetic data set
 - Generative Adversarial Networks
 - One-shot learning
- Protection
 - Logical obfuscation
 - Structural obfuscation

Questions



Matching using simulation vectors

- Permutation invariance
 - One-hot and two-hot vectors
 - Simulation graphs
 - Matching subgraphs



Matching using simulation vectors

- Permutation invariance
 - One-hot and two-hot vectors
 - Simulation graphs
 - Matching subgraphs
- Negation invariance
 - Add polarity variables
 - SAT problem

